

Silicon Carbide (SiC) Schottky Diode - EliteSiC, 10 A, 1200 V, D1, TO-247-2L

FFSH10120A

Description

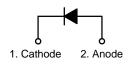
Silicon Carbide (SiC) Schottky Diodes use a completely new technology that provides superior switching performance and higher reliability compared to Silicon. No reverse recovery current, temperature independent switching characteristics, and excellent thermal performance sets Silicon Carbide as the next generation of power semiconductor. System benefits include highest efficiency, faster operating frequency, increased power density, reduced EMI, and reduced system size & cost.

Features

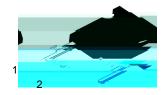
- Max Junction Temperature 175°C
- Avalanche Rated 100 mJ
- High Surge Current Capacity
- Positive Temperature Coefficient
- Ease of Paralleling
- No Reverse Recovery/No Forward Recovery
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- General Purpose
- SMPS, Solar Inverter, UPS
- Power Switching Circuits



Schottky Diode



TO-247-2LD CASE 340CL

MARKING DIAGRAM





A = Assembly Plant Code
YWW = Date Code (Year & Week)
ZZ = Lot Code
FFSH10120A = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

1

FFSH10120A

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter		Value	Unit
V_{RRM}	Peak Repetitive Reverse Voltage		1200	V
E _{AS}	Single Pulse Avalanche Energy (Note 1)		100	mJ
I _F	Continuous Rectified Forward Current @ T _C < 158°C		10	Α
	Continuous Rectified Forward Current @ T _C <	17		
I _{F, Max}	Non-Repetitive Peak Forward Surge Current	T _C = 25°C, 10 μs	850	Α
		T _C = 150°C, 10 μs	800	Α
I _{F,SM}	Non-Repetitive Forward Surge Current	$T_{C} < 158^{\circ}C$ $T_{C} < 135^{\circ}C$ Trent $T_{C} = 25^{\circ}C, 10 \mu s$ $T_{C} = 150^{\circ}C, 10 \mu s$ Half-Sine Pulse, $t_{p} = 8.3 m s$ $T_{C} = 25^{\circ}C$ $T_{C} = 150^{\circ}C$	90	А
I _{F,RM}	Repetitive Forward Surge Current		35	А
Ptot	Power Dissipation	T _C = 25°C	193	W
		T _C = 150°C	32	W
T _J , T _{STG}	Operating and Storage Temperature Range	•	-55 to +175	°C
	TO-247 Mounting Torque, M3 Screw		60	Ncm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. E_{AS} of 100 mJ is based on starting $T_J = 25^{\circ}C$, L = 0.5 mH, $I_{AS} = 20$ A, V = 50 V.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max	0.78	°C/W

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
V_{F}	Forward Voltage	I _F = 10 A, T _C = 25°C	-	1.45	1.75	V
		I _F = 10 A, T _C = 125°C	-	1.7	2.0	
		I _F = 10 A, T _C = 175°C	-	2.0	2.4	
I _R	Reverse Current	V _R = 1200 V, T _C = 25°C	-	-	200	μΑ
		V _R = 1200 V, T _C = 125°C	-	-	300	
		V _R = 1200 V, T _C = 175°C	-	-	400	
$Q_{\mathbb{C}}$	Total Capacitive Charge	V = 800 V	-	62	-	nC
С	Total Capacitance	V _R = 1 V, f = 100 kHz	-	612	-	pF
		V _R = 400 V, f = 100 kHz	-	58	_	
		V _R = 800 V, f = 100 kHz	-	47	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

ORDERING INFORMATION

Part Number	Top Marking	Package	Shipping
FFSH10120A	FFSH10120A	TO-247-2LD	

FFSH10120A

TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ UNLESS OTHERWISE NOTED})$

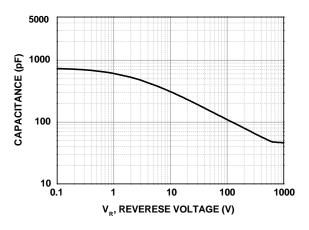


Figure 7. Capacitance vs. Reverse Voltage

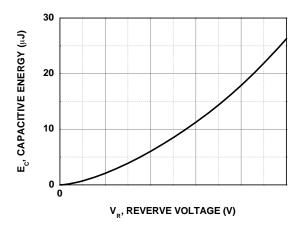


Figure 8. Capacitance Stored Energy

Figure 9. Junction-to-Case Transient Thermal Response Curve

FFSH10120A

TEST CIRCUIT AND WAVEFORMS

L = 0.5 mH $R < 0.1 \Omega$ $V_{DD} = 50 \text{ V}$ $EAVL = 1/2LI2 \left[V_{R(AVL)} / \left(V_{R(AVL)} - V_{DD} \right) \right]$ $Q1 = IGBT \left(BV_{CES} > DUT \ V_{R(AVL)} \right)$ V_{AVL} V_{AVL} V_{AVL} V_{AVL} V_{DD}

Figure 10. Unclamped Inductive Switching Test Circuit & Waveform



